

**Search Notes**

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

SHIGENO ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	22,23,29 30,32,33 35	3/8/2005	<i>SWH</i> SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR